

Siskiyou Corporation

With over 40 years experience, Siskiyou provides a diverse range of micromanipulators, microscope sample positioners, motion control systems, and modular opto-mechanical building blocks to life science and photonics researchers, enabling applications from precision beam control to patch clamping. As a company, our goal is simple—to offer the highest quality product at an economical price and to support our customers with superior service. All products are designed and manufactured in the United States—in Grants Pass, OR. We were the first company to offer 80 pitch adjusters and we are the only manufacturer of monolithic flexures for azimuth/elevation adjustment. Siskiyou specializes in putting many axes of adjustment in a small volume. Let us help build your next experiment!!

- Optomechanical components
- Precision adjusters from 20 pitch to 20 microns/turn
- Translation stages
- Motion control
- Fiber optic couplers
- Microscope translators
- Micromanipulators
- Test fixture components
- Compact microscope systems

Siskiyou serves primarily two markets. In the life science research community, we make products to support applications in electrophysiology, optogenetics, photoactivation, and imaging. For the laser marketplace, we supply optomechanical components for research, product development, and system manufacture, with both catalog and custom OEM products.



How to find us

Siskiyou Corporation
110 SW Booth St
Grants Pass, OR 97526
Tel: 541-479-8697
Email: sales@siskiyou.com
www.siskiyou.com

Living up to Life



https://doi.org/10.1017/S151929514000303 Published online by Cambridge University Press



Visit www.leica-microsystems.com/em-promos-MT to take advantage of Leica's current product promotions.



Image Analysis

Need Better SEM Images?

Your Image Starts Here! Leica Microsystems' workflow solutions deliver excellent quality throughout every step of the sample preparation process.

We offer the most comprehensive product portfolio for the preparation of biological and industrial samples for examination in the Electron Microscope (SEM – Scanning Electron Microscope and TEM – Transmission Electron Microscope), LM (Light Microscope), Confocal Microscope, and AFM (Atomic Force Microscope).

www.leica-microsystems.com